

Notice of References Cited	Application/Control No. 09/548,637	Applicant(s)/Patent Under Reexamination KOZA ET AL.	
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U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Koza et al ("AUTOMATED DESIGN OF BOTH THE TOPOLOGY AND SIZING OF ANALOG ELECTRICAL CIRCUITS USING GENETIC PROGRAMMING" 1996)
	V	Singh et al ("matching structural shape descriptions using genetic algorithms, 1997
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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*	U	Thompson et al ("Explorations in design space: Unconventional electronics design through artificial evolution" 1999)
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